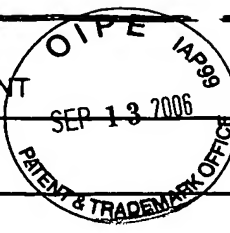


Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
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ATTY DOCKET NO.

248760US0RDCONT

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New Continuation of
10/188,744

LIST OF REFERENCES CITED BY APPLICANT

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Yasuo OHBA

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U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA	4,792,958	12/20/88	OHBA, et al.			
	AB	4,809,287	02/28/89	OHBA, et al.			
	AC	4,835,117	05/30/89	OHBA, et al.			
	AD	4,949,349	08/14/90	OHBA, et al.			
	AE	4,910,743	03/20/90	OHBA, et al.			
	AF	4,928,285	05/22/90	KUSHIBE, et al.			
	AG	4,893,313	01/09/90	HATAKOSHI, et al.			
	AH	5,076,800	12/31/91	MILNES, et al.			
	AI	5,036,521	07/30/91	HATAKOSHI, et al.			
	AJ	5,168,077	12/01/92	ASHIZAWA, et al.			
	AK	5,042,043	08/20/91	HATANO, et al.			
	AL	5,005,057	04/02/91	IZUMIYA, et al.			
	AM	5,079,184	01/07/92	HATANO, et al.			
	AN	5,103,271	04/07/92	IZUMIYA, et al.			

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
	AO	2000-31588	01/28/00	JAPAN		
	AP					
	AQ					
	AR					
	AS					
	AT					
	AU					
	AV					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	Y. OHBA, et al., Japanese Journal of Applied Physics, Vol. 37 Part 2, No. 8A, pp. L 905 - L 906, "FABRICATION AND CHARACTERIZATION OF AlGaIn/GaN DOUBLE-HETEROLASER STRUCTURES ON SAPPHIRE SUBSTRATES USING SINGLE CRYSTALLINE AlN BUFFER LAYERS," August 1, 1998.
	AX	
	AY	
	AZ	

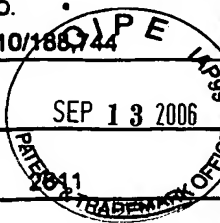
☐ Additional References sheet(s) attached

Examiner

Date Considered

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 225255US0RD		SERIAL NO. 10/188,744	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Yasuo OHBA			
				FILING DATE July 5, 2002			
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>[initials]</i>	AA	6,242,764	06/05/2001	Y. OHBA, et al.			
<i>[initials]</i>	AB	5,990,495	11/23/99	Y. OHBA			
<i>[initials]</i>	AC	5,656,832	08/12/97	Y. OHBA, et al.			
<i>[initials]</i>	AD	5,909,040	06/01/99	Y. OHBA, et al.			
<i>[initials]</i>	AE	5,929,466	07/27/99	Y. OHBA, et al.			
	AF						
	AG						
	AH						
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	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
<i>[initials]</i>	AO	2000-31588	01/28/2000	JAPAN (with English Abstract)			X
	AP						
	AQ						
	AR						
	AS						
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	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
<i>[initials]</i>	AW	Y. OHBA, et al., Japanese Journal of Applied Physics, Vol. 37 Part 2, No. 8A, pps. L 905-L 906, "FABRICATION AND CHARACTERIZATION OF AlGaIn/GaN DOUBLE-HETEROLASER STRUCTURES ON SAPPHIRE SUBSTRATES USING SINGLE CRYSTALLINE AlN BUFFER LAYERS," August 1, 1998					
	AX						
	AY						
	AZ	<input type="checkbox"/> Additional References sheet(s) attached					
Examiner <i>J. MONDT</i>					Date Considered <i>02/05/03.</i>		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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